## **AMENDMENTS TO THE CLAIMS**

- 1. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P.
- 2. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P and 0.01-2.0 mass% of at least one metallic element selected from In, Sn and Zn.
- 3. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P, 0.01-0.9 mass% of Au and/or 0.001-5.0 mass% of Pd and/or 0.01-0.9 mass% of Pt.
- 4. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P and 0.01-5.0 mass% of at least one metallic element selected from Cu, Ni, Fe and Bi.
- 5. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P, 0.01-2.0 mass% of at least one metallic element selected from In, Sn and Zn, 0.01 to 0.9 mass% of Au and /or 0.01-5.0 mass% of Pd and/or 0.01-0.9 mass% of Pt.

- 6. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P, 0.01-2.0 mass% of at least one metallic element selected from In, Sn and Zn, and 0.01-5.0 mass% of at least one metallic element selected from Cu, Ni, Fe and Bi.
- 7. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P, 0.01-0.9 mass% of Au and/or 0.01-5.0 mass% of Pd and/or 0.01-0.9 mass% of Pt, and 0.01-5.0 mass% of at least one metallic element selected from Cu, Ni, and Bi.
- 8. (Currently Amended) A thin film-forming sputtering target material having high reflectance, characterized by beingsaid material being composed of an Ag base alloy containing 0.0058-1.0 mass% of P, 0.01-2.0 mass% of at least one metallic element selected from In, Sn and Zn, 0.01-0.9 mass% of Au and/or 0.01-5.0 mass% of Pd and/or 0.01-0.9 mass% of Pt, and 0.01-5.0 mass% of at least one metallic element selected from Cu, Ni, Fe and Bi.
- 9. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 1.
- 10. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 2.
- 11. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 3.
- 12. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 4.
- 13. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 5.
- 14. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 6.

- 15. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 7.
- 16. (Previously Presented) Thin film formed of an Ag base alloy as set forth in Claim 8.